NOTES:

- 1. SUBSTRATE: UV FUSED SILICA
- 2. SURFACE S2 TO BE PARALLEL WITH SURFACE S1 TO WITHIN 5 arcsec
- 3. COATING (APPLY ACROSS COATING APERTURE)

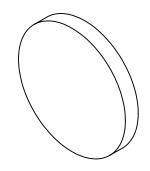
\$1: HARD DIELECTRIC \$PUTTERED T(avg): ≥91% FROM 890 - 1650nm @ 0° AOI T(avg): ≤0.01% FROM 200 - 860nm @ 0° AOI T(abs): =50% FOR 875±8.75nm @ 0° AOI

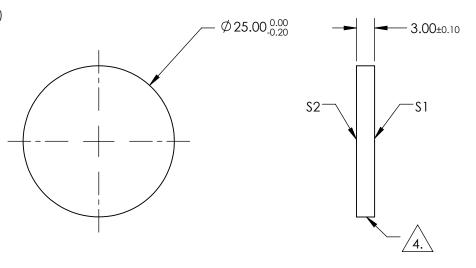
S2:SINGLE LAYER MgF2

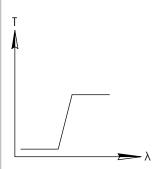
4.\FINE GRIND SURFACE

- 5. POWER, IRREGULARITY, AND SURFACE QUALITY SPECIFICATIONS APPLY ACROSS CLEAR APERTURE
- 6. TRANSMITTED WAVEFRONT DISTORTION, RMS: ≤λ/4 @ 633nm (prior to coating)
- 7. ROHS COMPLIANT









LONGPASS FILTER

	\$1	\$2		
SHAPE	PLANO	PLANO		
SURFACE QUALITY	60-40	60-40		
CLEAR APERTURE	>80%	>80%		
BEVEL	PROTECTIVE AS NEEDED			

SPECIFICATIONS SUBJECT TO CHANGE WITHOUT NOTICE DIMENSIONS ARE FOR REFERENCE ONLY

Pan® Edmund Optics®

THIRD ANGLE PROJECTION	ϕ	TITLE	Ø25mm, 875nm, HIGH PERFOR LONGPASS FILTER	MANCE	
ALL DIMS IN	mm	DWG NO	86071	SHEET 1 OF 1	